11th IEEE International Conference on Industrial Informatics (INDIN'2013)

July 29-31, 2013, Bochum, Germany

Special Session on
Ensuring Safety in Industrial Critical Systems (ESICS)

– CALL FOR PAPERS –

In many safety-critical industrial areas, such as the automotive, railway, aerospace or automation industry, E/E systems have become indispensable. Due to the increasing complexity of those systems ensuring their safe operation has become a challenge.

This session will be focusing on (but not limited to) the following topics:

- Approaches to the design of safe E/E systems
- Validation & verification of safety-critical systems
- Industrial case studies
- Development of certifiable E/E systems
- Tools for ensuring safe E/E systems
- Formal Methods and formalization of requirements
- Model-checking, model-based testing and test case generation

We welcome contributions from both, academia and industry.

Paper submission

The working language of the conference is English. Prospective participants are requested to submit full papers of their work (6 pages max.) following the instructions available on the conference website. Accepted papers will be included in conference proceedings volume, which will be submitted to be published in IEEE Xplore. Please use the templates provided with this link for your paper preparation:
http://www.ieee.org/conferences_events/conferences/publishing/templates.html

Important dates

Deadline for submission of papers: .... **February 28, 2013**
Notification of acceptance: .... **April 19, 2013**
Deadline for submission of final manuscripts: .... **May 24, 2013**

Organizers

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